

Supporting Information

Dual-Functional Optoelectronic Memories Based on Ternary Hybrid Floating Gate Layers

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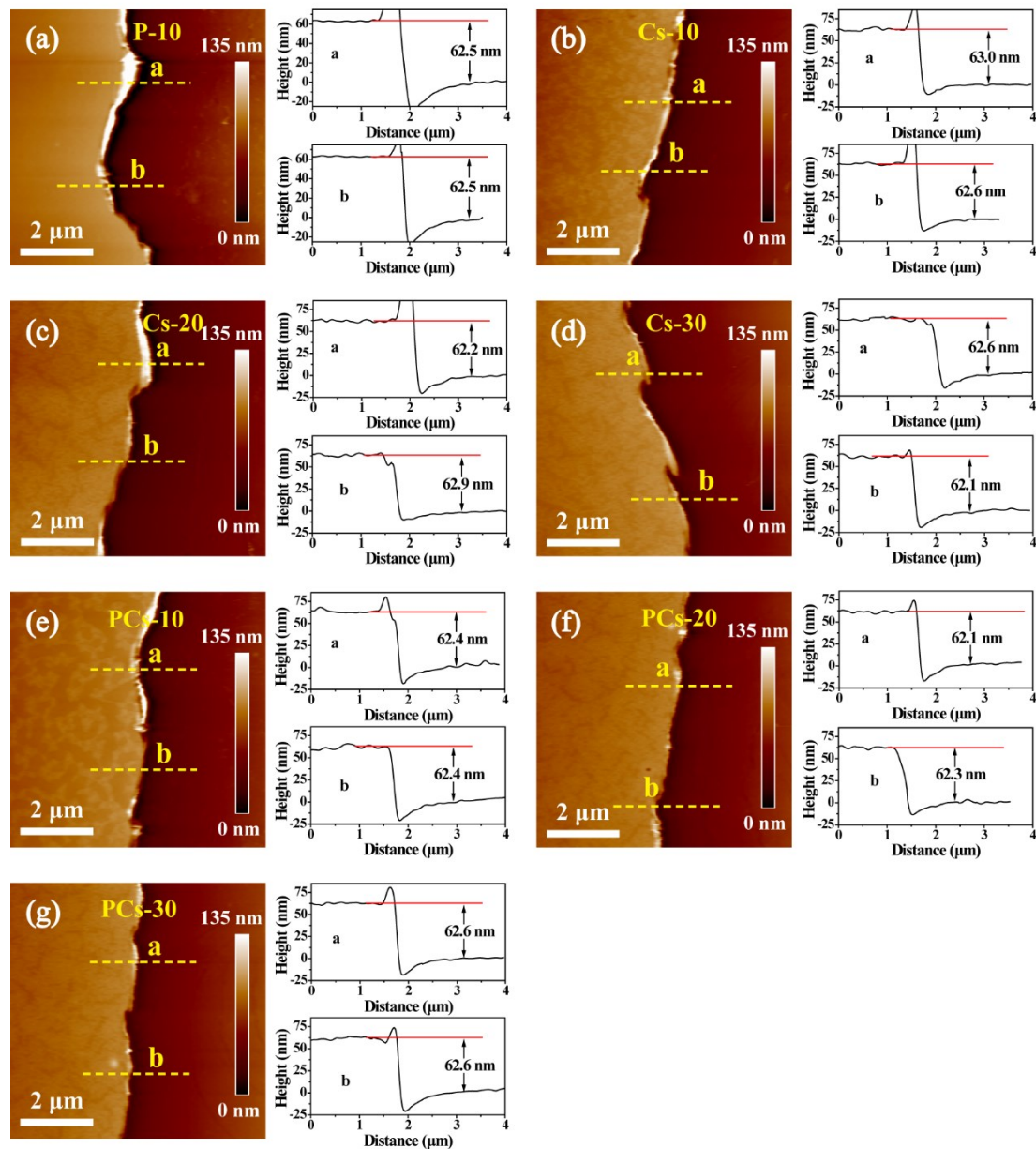


Fig. S1 AFM height images of (a) P-10, (b) Cs-10, (c) Cs-20, (d) Cs-30, (e) PCs-10, (f) PCs-20, and (g) PCs-30 films on SiO₂, corresponding cross-sectional height profiles of different composite films.

The films were slit by a needle and the thicknesses of different composite films on SiO₂ were measured by AFM. As shown in Fig. S1, the thicknesses of different composite layers are about 62–63 nm, which are not much different, eliminating the effect of thicknesses on memory windows.

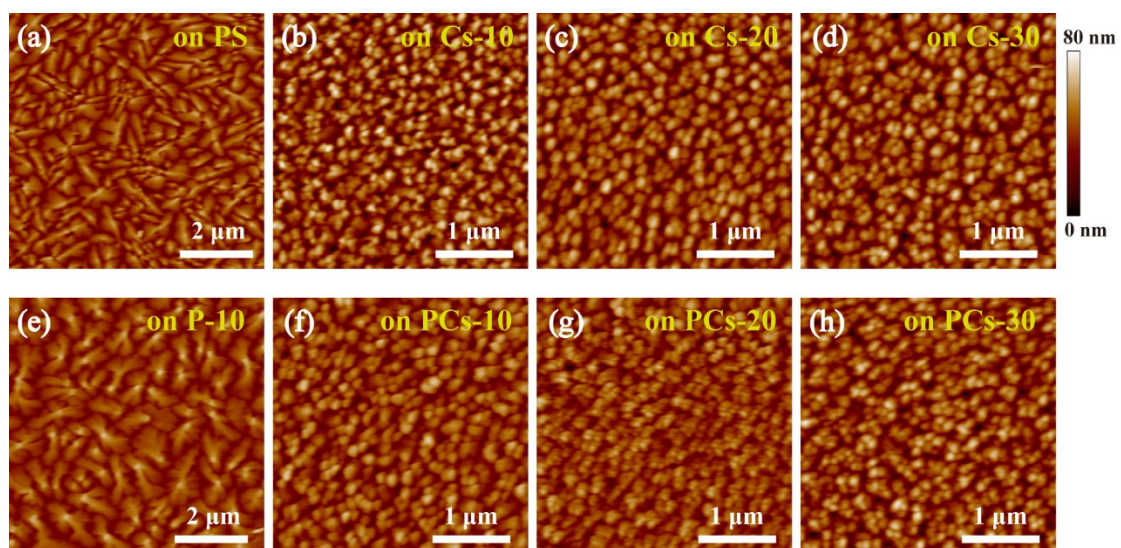


Fig. S2 AFM images of the pentacene grown on (a) PS, (b) Cs-10, (c) Cs-20, (d) Cs-30, (e) P-10, (f) PCs-10, (g) PCs-20, and (h) PCs-30 films.

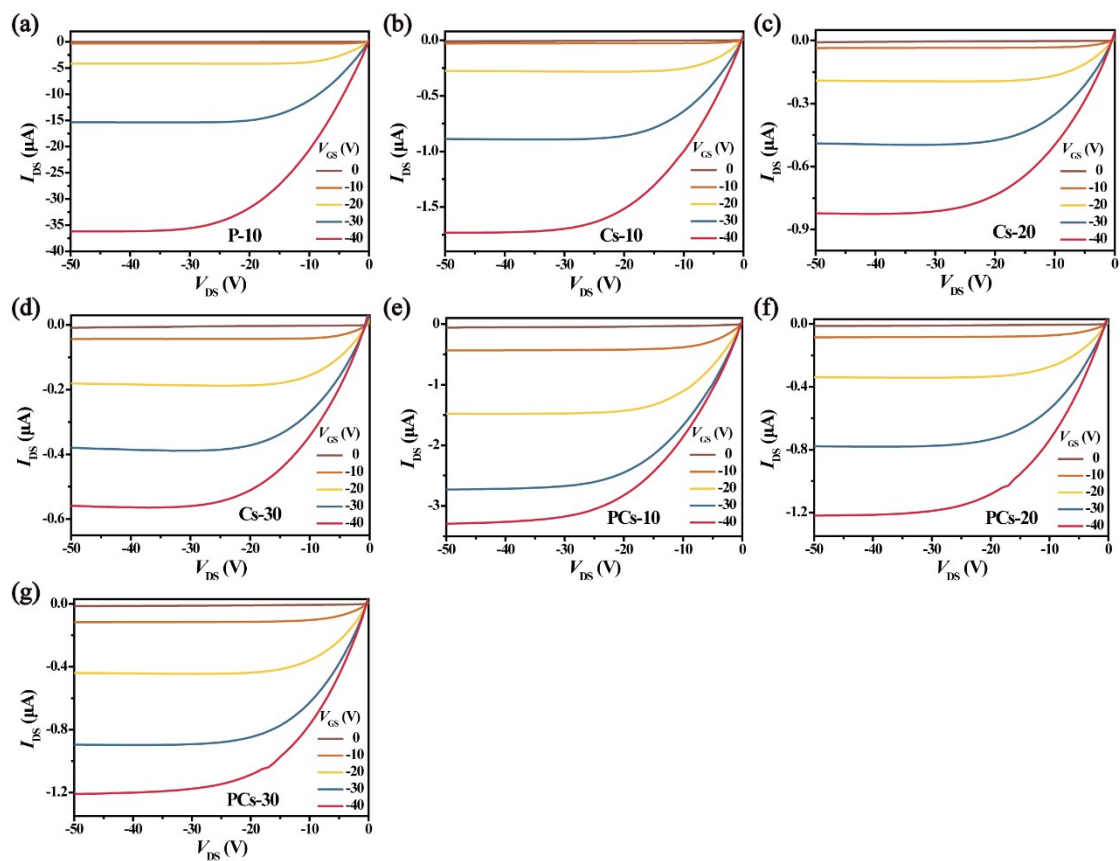


Fig. S3 Output characteristics of (a) P-10, (b) Cs-10, (c) Cs-20, (d) Cs-30, (e) PCs-10, (f) PCs-20, and (g) PCs-30 memory devices.

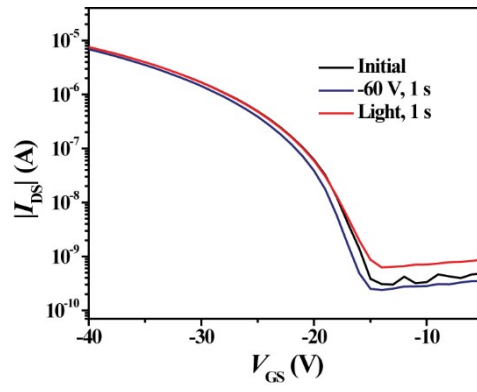


Fig. S4 Transfer characteristics of PS based device under different operations.

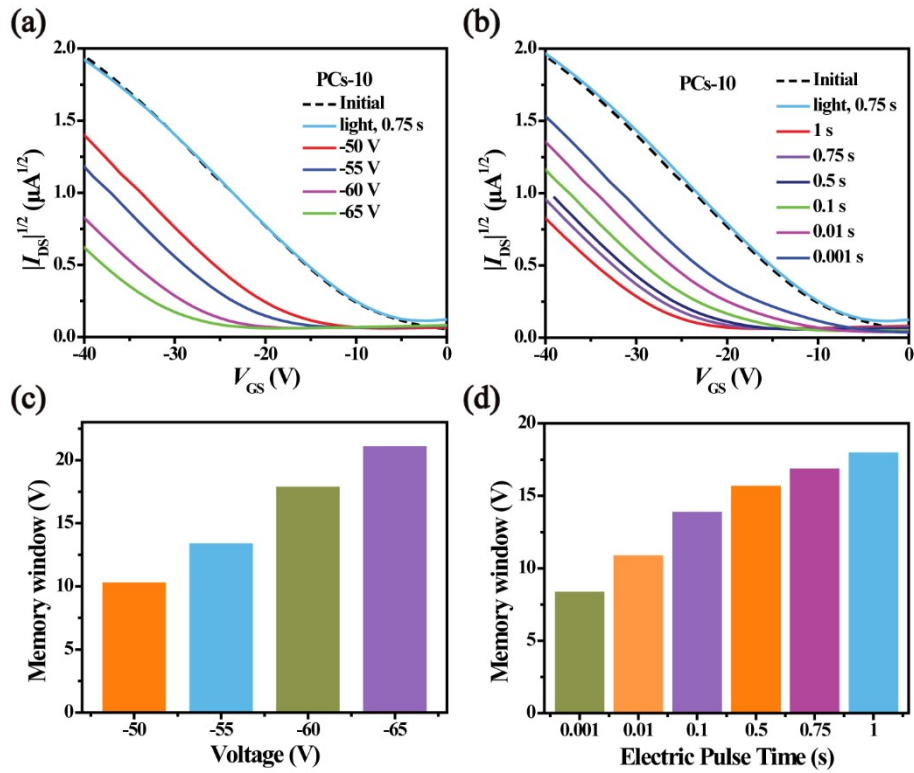


Fig. S5 Transfer characteristics of PCs-10 memory device under electric programming operations with different (a) gate biases for 1 s and (b) electric pulse time ($V_{GS} = -60$ V). Corresponding memory windows varied with the (c) programming voltages and (d) electric pulse time.

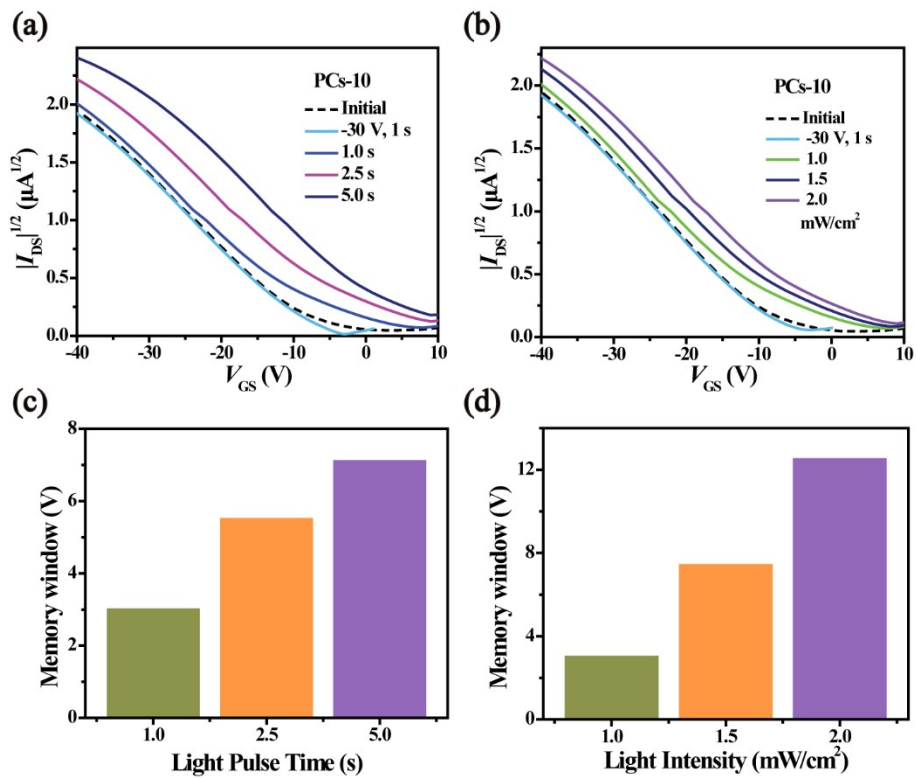


Fig. S6 Transfer characteristics of PCs-10 memory device under photoprogramming operations with different (a) illumination time (light intensity: 1 mW/cm^2) and (b) light intensities (illumination time: 1 s). Corresponding memory windows varied with the (c) illumination time and (d) light intensities.

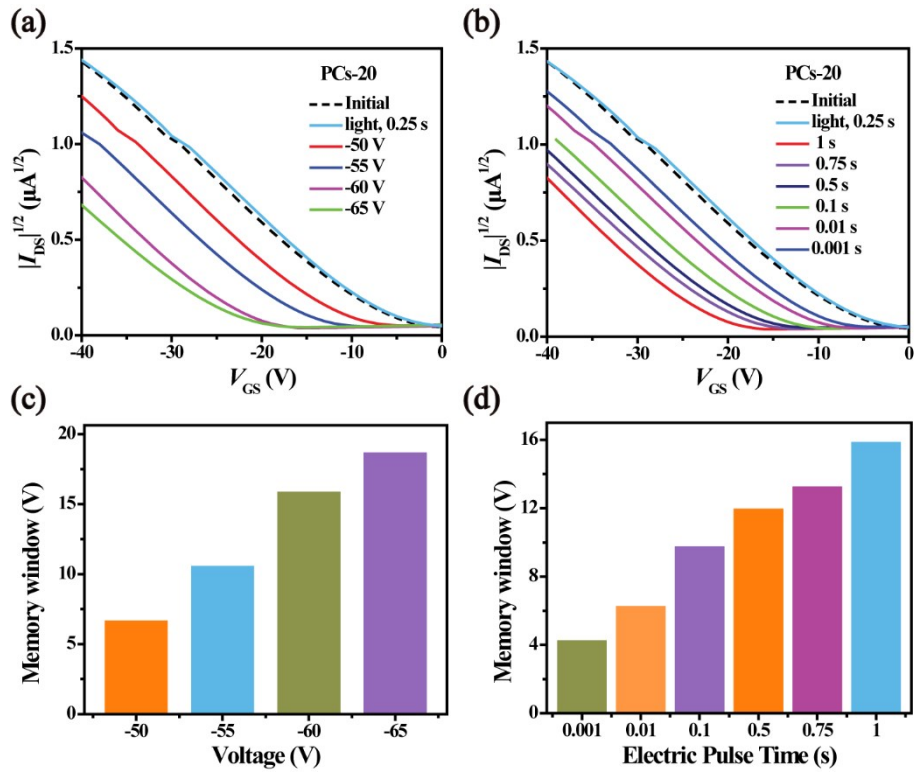


Fig. S7 Transfer characteristics of PCs-20 memory device under electric programming operations with different (a) gate biases for 1 s and (b) electric pulse time ($V_{GS} = -60$ V). Corresponding memory windows varied with the (c) programming voltages and (d) electric pulse time.

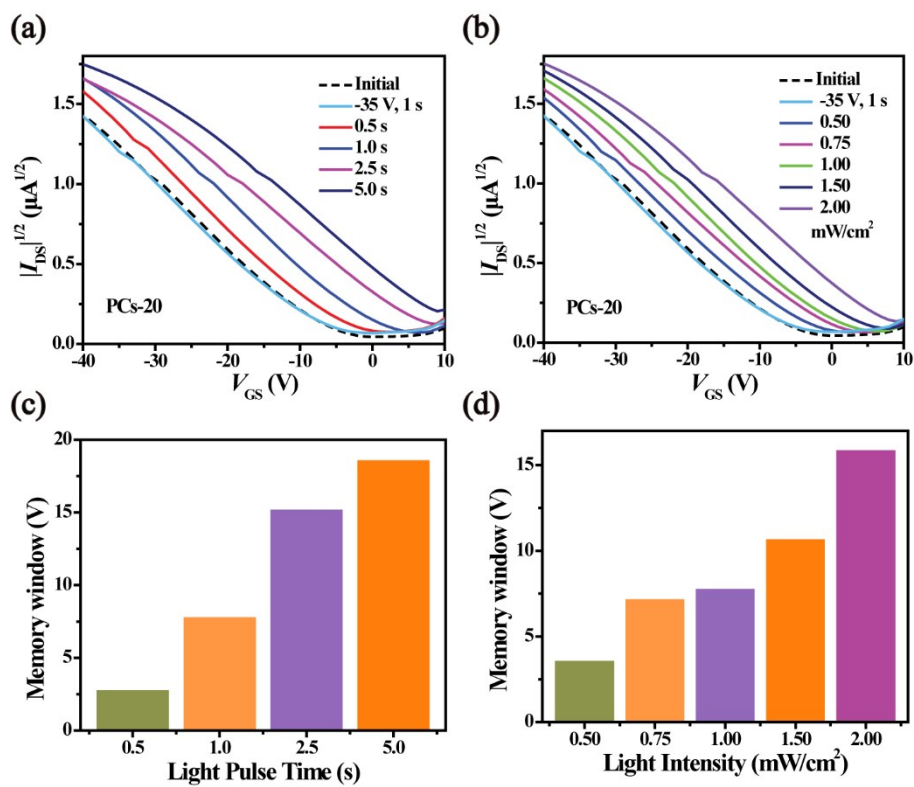


Fig. S8 Transfer characteristics of PCs-20 memory device under photoprogramming operations with different (a) illumination time (light intensity: 1 mW/cm^2) and (b) light intensities (illumination time: 1 s). Corresponding memory windows varied with the (c) illumination time and (d) light intensities.